## Notice of References Cited

Application/Control No. 10/735,931	Reexaminati	Applicant(s)/Patent Under Reexamination TISCHER, STEVEN		
Examiner	Art Unit			
Awet A. Haile	2616	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,958,081 A	05-1976	Ehrsam et al.	380/29
*	В	US-5,742,684 A	04-1998	Labaton et al.	705/72
*	С	US-2002/0116608 A1	08-2002	Wheeler et al.	713/155
*	D	US-2004/0059921 A1	03-2004	Bianchi, Jean-Pierre	713/185
*	E	US-2004/0049702 A1	03-2004	Subramaniam et al.	713/201
*	F	US-2004/0107350 A1	06-2004	Wasilewski et al.	713/182
*	G	US-6,853,620 B2	02-2005	Mauritz et al.	370/237
*	Н	US-2005/0257055 A1	11-2005	Anderson, Eric C.	713/170
*	J	US-2007/0005955 A1	01-2007	Pyle et al.	713/156
*	J	US-7,215,771 B1	05-2007	Hamlin, Christopher L.	380/44
	К	US-			
	L	US-			,
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			· ·		
	Р					
	Q					
	R					
	S					
	Т		,			

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	·
:	U		
	V		
	w		
	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.